



Form 1449 (Modified) Information Disclosure Statement By Applicant (Use Several Sheets if Necessary)	Atty Docket No. ALTRP104/A1212	Application No.: 10/727,781
	Applicant: Gray et al.	
	Filing Date December 3, 2003	Group 2857

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
	A1						
	A2						
	A3						
	A4						
	A5						

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
							Yes	No
	B1							
	B2							
	B3							
	B4							
	B5							

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
BPB	C1	Tehrani pour et al., "Embedded Test for Processor and Memory Cores in System-on-Chips", VLSI Circuits and Systems Laboratory, Dept of ECE, The University of Tehran," September 2003 .
BPB	C2	Campenhout et al., "High-Level Test Generation for Design Verification of Pipelined Microprocessors", ACM 1-58113-109-7/99/06, 1999
	C3	
Examiner <i>Bruce P. Boon</i>		Date Considered <i>6/14/07</i>

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.